

## P-Channel MOSFET MEM2307XG

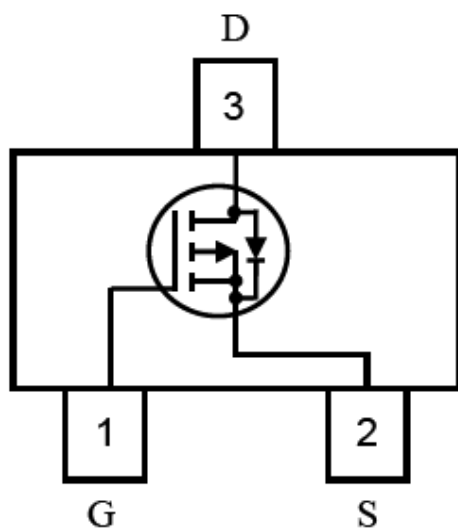
### General Description

MEM2307XG Series P-channel enhancement mode field-effect transistor, produced with high cell density DMOS trench technology, which is especially used to minimize on-state resistance. This device particularly suits low voltage applications, and low power dissipation, and low power dissipation in a very small outline surface mount package.

### Features

- -30V/-4.1A
- $R_{DS(ON)} < 88m\Omega @ V_{GS} = -10V, I_D = -4.1A$
- $R_{DS(ON)} < 108m\Omega @ V_{GS} = -4.5V, I_D = -3A$
- High Density Cell Design For Ultra Low On-Resistance
- Subminiature surface mount package: SOT23

### Pin Configuration



### Typical Application

- Power management
- Load switch
- Battery protection

### Absolute Maximum Ratings

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		$V_{DSS}$	-30V	V
Gate-Source Voltage		$V_{GSS}$	$\pm 20$	V
Drain Current	$T_A = 25^\circ C$	$I_D$	-4.1	A
	$T_A = 70^\circ C$		-3.5	
Pulsed Drain Current <sup>1,2</sup>		$I_{DM}$	-20	A
Total Power Dissipation	$T_A = 25^\circ C$	Pd	1.4	W
	$T_A = 70^\circ C$		1	
Operating Temperature Range		$T_{Opr}$	150	$^\circ C$
Storage Temperature Range		$T_{stg}$	-55/150	$^\circ C$

## Thermal Characteristics

Parameter		Symbol	TYP.	MAX.	Unit
Thermal Resistance, Junction-to-Ambient	$t \leq 10s$	$R_{\theta JA}$	65	90	$^{\circ}C/W$
Thermal Resistance, Junction-to-Ambient	Steady-State	$R_{\theta JA}$	85	125	$^{\circ}C/W$
Thermal Resistance, Junction-to-Lead	Steady-State	$R_{\theta JL}$	43	60	$^{\circ}C/W$

## Electrical Characteristics

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=-250\mu A$	-30			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1	-1.3	-2	V
Gate-Body Leakage	$I_{GSS}$	$V_{DS}=0V, V_{GS}=20V$			100	nA
		$V_{DS}=0V, V_{GS}=-20V$			-100	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=-24V, V_{GS}=0V$			-1000	nA
Static Drain-Source On-Resistance	$R_{DS(ON)1}$	$V_{GS}=-10V, I_D=-4.1A$			88	m $\Omega$
	$R_{DS(ON)2}$	$V_{GS}=-4.5V, I_D=-3A$			108	m $\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS} = -5V, I_D = -4A$	5.5	8.2		S
Maximum Body-Diode Continuous Current	$I_S$				-2.2	A
Source-drain (diode forward) voltage	$V_{SD}$	$V_{GS}=0V, I_S=-1A$		0.77	-1.0	V
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{iss}$	$V_{GS}=0V, V_{DS}=-15V, f=1MHz$		700	840	pF
Output Capacitance	$C_{oss}$			120		
Reverse Transfer Capacitance	$C_{rss}$			75		
Gate resistance	$R_g$	$V_{GS}=0V, V_{DS}=0V, f=1MHz$		10	15	$\Omega$
<b>Switching Characteristics</b>						
Turn-On Delay Time	$t_d(on)$	$V_{GS}=-10V, V_{DS}=-15V, R_L=3.6\Omega, R_{GEN}=6\Omega$		8.6		ns
Rise Time	$t_r$			5		
Turn-Off Delay Time	$t_d(off)$			28.2		
Fall-Time	$t_f$			13.5		
Total Gate Charge	$Q_g$	$V_{DS} = -15V, V_{GS} = -4.5V, I_D = -4A$		14.3		nC
Gate-Source Charge	$Q_{gs}$			3.1		
Gate-Drain Charge	$Q_{gd}$			3		

1、Repetitive rating, pulse width limited by junction temperature.

2、The static characteristics are obtained using 80  $\mu s$  pulses, duty cycle 0.5% max.

Typical Performance Characteristics

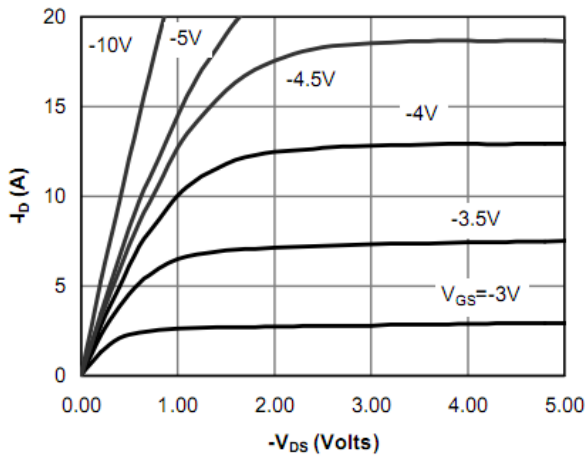


Figure 1: On-Region Characteristics

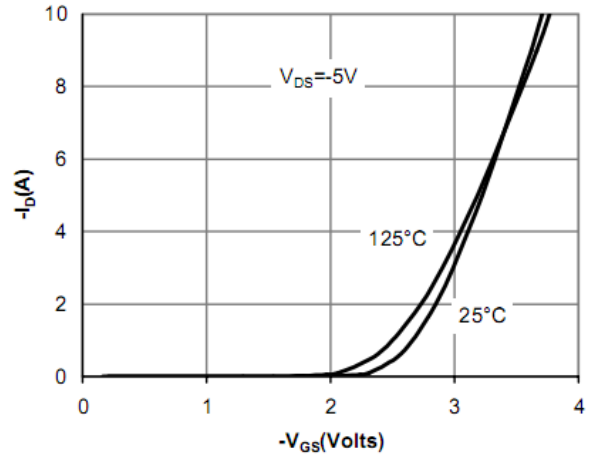


Figure 2: Transfer Characteristics

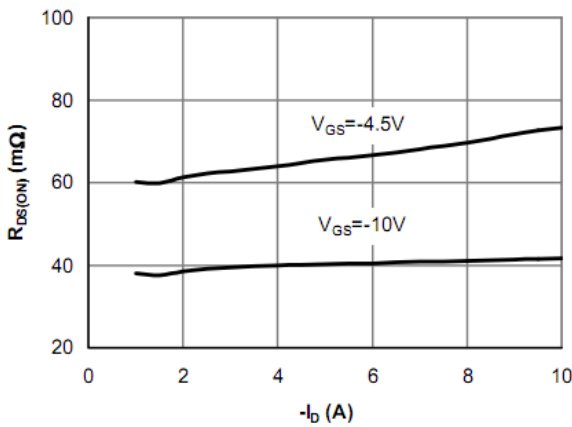


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

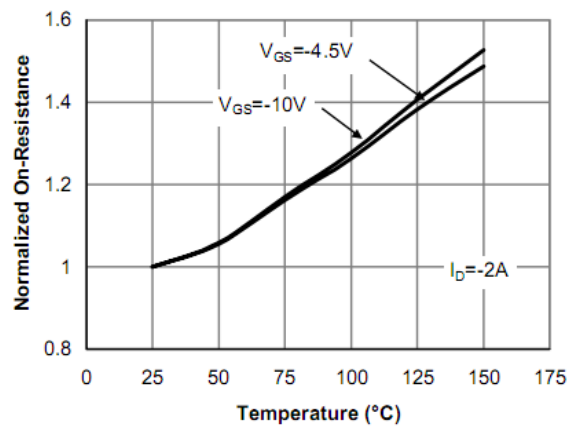


Figure 4: On-Resistance vs. Junction Temperature

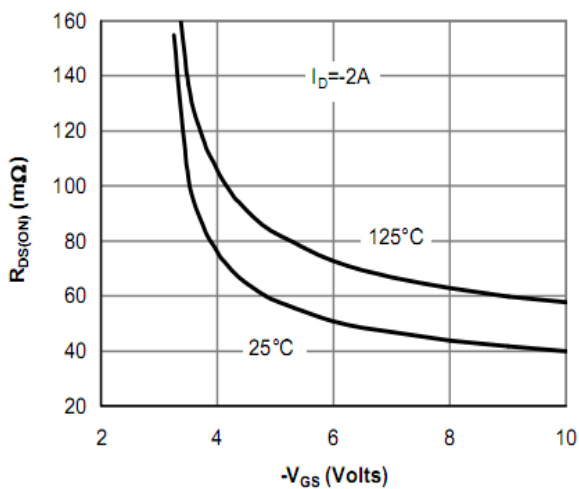


Figure 5: On-Resistance vs. Gate-Source Voltage

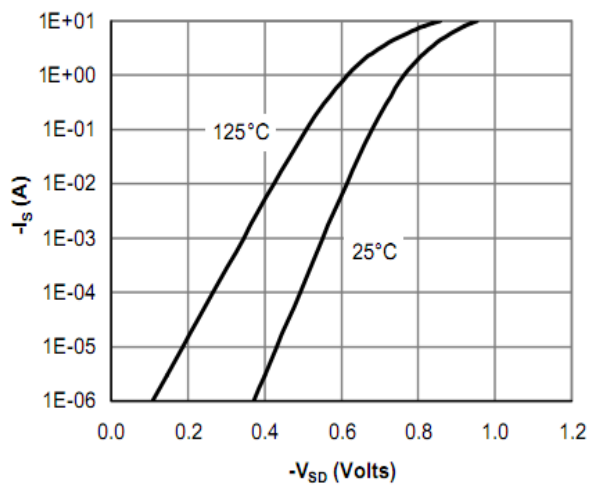


Figure 6: Body-Diode Characteristics

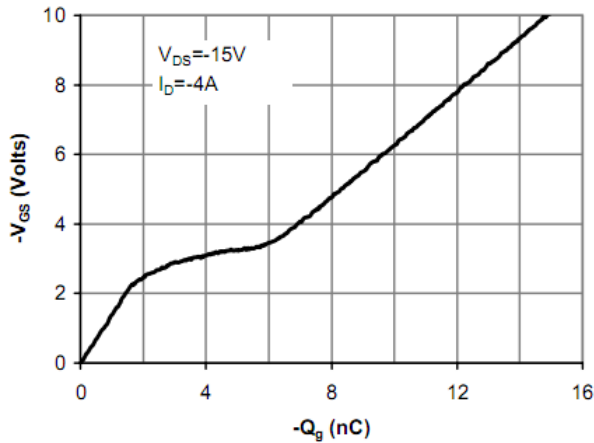


Figure 7: Gate-Charge Characteristics

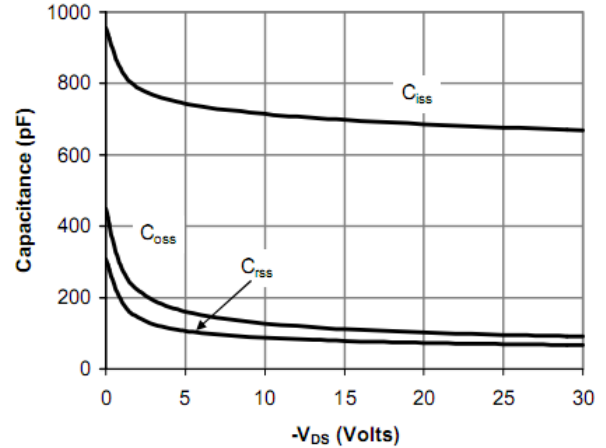


Figure 8: Capacitance Characteristics

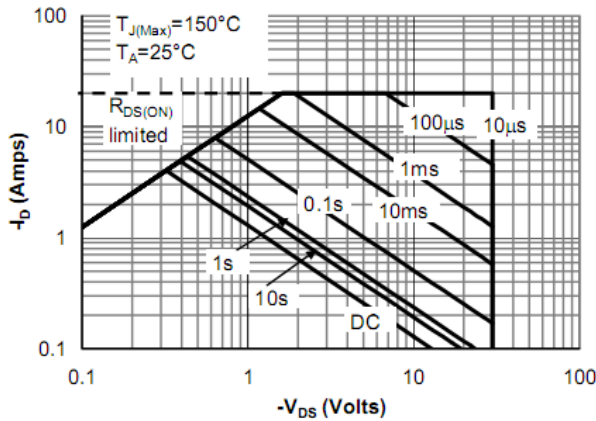


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

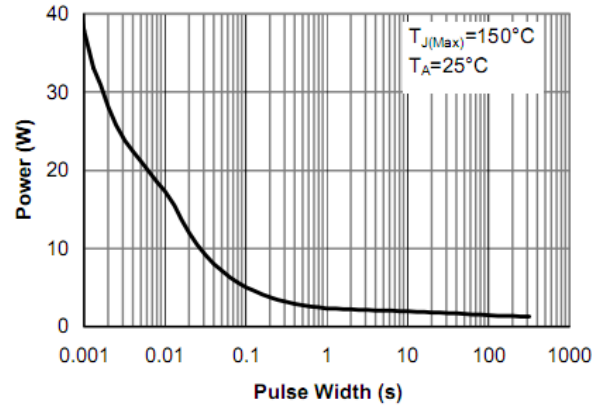


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

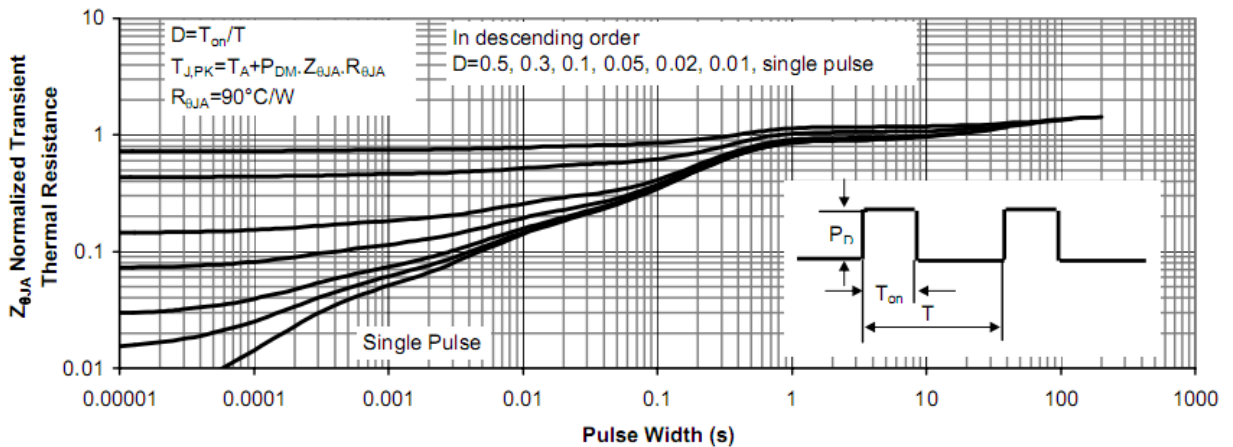
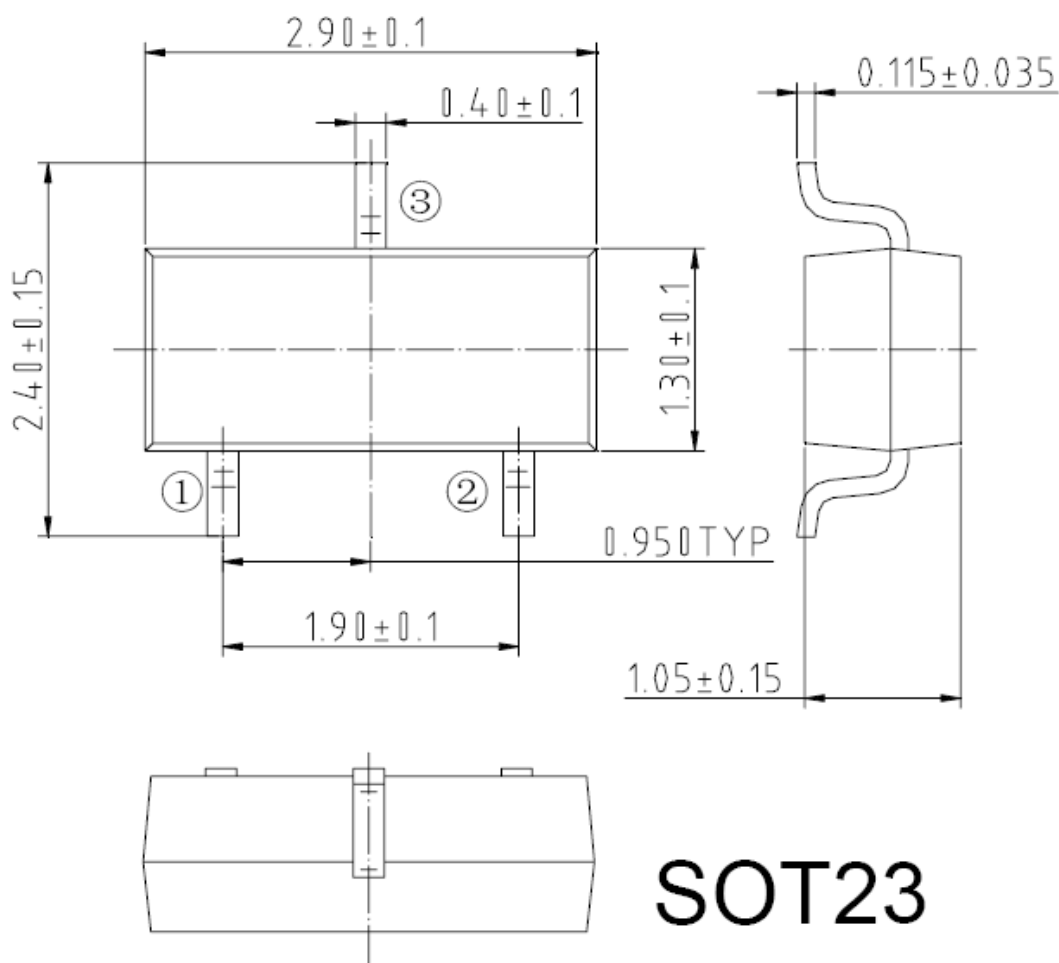


Figure 11: Normalized Maximum Transient Thermal Impedance

Package Information



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